

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Currently Amended) An optical characteristic measuring instrument that measures an optical characteristic of a device under test, comprising:

a polarization ~~separating means~~ separator that receives light having emitted from the device under test, separates the received light into p-polarized light and s-polarized light, and outputs the p-polarized light and s-polarized light;

a light ~~generating means~~ generator that generates incident light;

an optical ~~modulation means~~ modulator that applies intensity modulation to the incident light, and emits modulated light;

a light ~~input means~~ inputter that makes the incident light which has undergone the intensity modulation incident on the device under test, wherein the incident light is coincident with a p-polarization axis and an s-polarization axis of said polarization ~~separating means~~ separator;

a first ~~measuring means~~ measurer that measures a phase shift equivalent value and an amplitude equivalent value of the incident light based upon the output from said polarization ~~separating means~~ separator;

a second ~~measuring means~~ measurer that measures a phase shift equivalent value of the incident light based upon the light emitted from the device under test; and

an optical characteristic ~~measuring means~~ measurer that measures the optical characteristic of the device under test based upon the measured results by said first ~~measuring means~~ measurer and said second ~~measuring means~~ measurer.

2. (Currently Amended) The optical characteristic measuring instrument according to claim 1, wherein the optical characteristic ~~measuring means~~ measurer measures the optical characteristic of the device under test based upon the measured result by said second ~~measuring means~~ measurer if a p-polarization component of the of the amplitude equivalent value of the incident light measured by said first ~~measuring means~~ measurer being excessively large or excessively small compared with that of an s-polarization component thereof.

3. (Previously Presented) The optical characteristic measuring instrument according to claim 1, wherein the phase shift equivalent value is obtained by differentiating a phase shift by an optical angular frequency.

4. (Previously Presented) The optical characteristic measuring instrument according to claim 1, wherein the amplitude equivalent value is the square of an amplitude.

5. (Currently Amended) The optical characteristic measuring instrument according to claim 3, wherein a group delay time ~~measuring means that~~ measurer measures a group delay time of the device under test based upon the measured result by said second ~~measuring means~~ measurer.

6. (Currently Amended) An optical characteristic measuring method for measuring an optical characteristic of a device under test, comprising:

~~a polarization separating step of receiving light having emitted from~~
the device under test~~[[,]]~~_i

separating the received light into p-polarized light and s-polarized light~~[[,]]~~ and_i

outputting the p-polarized light and s-polarized light;

~~a light generating step of generating incident light;~~

~~an optical modulation step of~~ applying intensity modulation to the incident light~~[[,]]~~ and emitting modulated light;

~~a light input step of making the incident light which has undergone~~
the intensity modulation incident on the device under test_i, wherein the incident light is coincident with a p-polarization axis and an s-polarization

axis of said ~~polarization separating step~~ p-polarized light and s-polarized light;

~~a first measuring step of measuring a phase shift equivalent value and an amplitude equivalent value of the incident light based upon the output from said polarization separating step~~ p-polarized light and s-polarized light;

~~a second measuring step of measuring a phase shift equivalent value of the incident light based upon the light emitted from the device under test; and~~

~~an optical characteristic measuring step of measuring the optical characteristic of the device under test based upon the measured results by said first measuring step and said second measuring step~~ measured phase shift equivalent value and amplitude equivalent value of the incident light based upon the p-polarized light and s-polarized light, and the measured phase shift equivalent value of the incident light based upon the light emitted from the device under test.

7. (Currently Amended) A program of instructions for execution by the a computer to perform an optical characteristic measuring process of an optical characteristic measuring instrument that measures an optical characteristic of a device under test, ~~having~~ comprising: a polarization separating means separator that receives light ~~having been~~ emitted from the device under test, separates the received light into p-polarized light and s-polarized light, and outputs the p-polarized light and s-polarized light; a

~~light generating means~~ generator that generates incident light; an optical ~~modulation means~~ modulator that applies intensity modulation to the incident light, and emits modulated light; and a light ~~input means~~ inputter that makes the incident light which has undergone the intensity modulation incident on the device under test, wherein the incident light is coincident with a p-polarization axis and an s-polarization axis of said polarization ~~separating means~~ separator;

said optical characteristic measuring process comprising:

~~a first measuring step of~~ measuring a phase shift equivalent value and an amplitude equivalent value of the incident light based upon the output from said polarization ~~separating step~~ separator;

~~a second measuring step of~~ measuring a phase shift equivalent value of the incident light based upon the light emitted from the device under test; and

~~an optical characteristic measuring step of~~ measuring the optical characteristic of the device under test based upon the ~~measured results by~~ ~~said first measuring step and said second measuring step~~ measured phase shift equivalent value and amplitude equivalent value of the incident light based output from said polarization separator, and the measured phase shift equivalent value of the incident light based upon the light emitted from the device under test.

8. (Currently Amended) A computer-readable medium having a program of instructions for execution by the a computer to perform an

optical characteristic measuring process of an optical characteristic measuring instrument that measures an optical characteristic of a device under test, ~~having comprising~~: a polarization ~~separating means~~ separator that receives light ~~having emitted~~ from the device under test, separates the received light into p-polarized light and s-polarized light, and outputs the p-polarized light and s-polarized light; a light ~~generating means~~ generator that generates incident light; an optical ~~modulation means~~ modulator that applies intensity modulation to the incident light, and emits modulated light; and a light ~~input means~~ inputter that makes the incident light which has undergone the intensity modulation incident on the device under test wherein the incident light is coincident with a p-polarization axis and an s-polarization axis of said polarization ~~separating means~~ separator;

said optical characteristic measuring process comprising:

~~a first measuring step of~~ measuring a phase shift equivalent value and an amplitude equivalent value of the incident light based upon the output from said polarization ~~separating step~~ separator;

~~a second measuring step of~~ measuring a phase shift equivalent value of the incident light based upon the light emitted from the device under test; and

~~an optical characteristic measuring step of~~ measuring the optical characteristic of the device under test based upon the ~~measured results by said first measuring step and said second measuring step~~ measured phase shift equivalent value and amplitude equivalent value of the incident light based output from said polarization separator, and the measured phase shift

equivalent value of the incident light based upon the light emitted from the device under test.

9. (Previously Presented) The optical characteristic measuring instrument according to claim 2, wherein the phase shift equivalent value is obtained by differentiating a phase shift by an optical angular frequency.

10. (Previously Presented) The optical characteristic measuring instrument according to claim 2, wherein the amplitude equivalent value is the square of an amplitude.

11. (Currently Amended) The optical characteristic measuring instrument according to claim 9, wherein a group delay time ~~measuring means that~~ measurer measures a group delay time of the device under test based upon the measured result by said second ~~measuring means~~ measurer.